# UNIT TEST-I (2010-11)

CLASS:- BE(E & TC) SUB:- VLSI DESIGN MARKS:-30

- Q1. Differentiate function and procedure. what do you mean by subprogram overloading.(9) OR
- Q1. Write VHDL codes for 8:1mux using 2:1 mux with structural modeling .(9)
- Q2. Explain any two attributes in detail.(6)
- Q3. What do you mean by metastability? what are the solutions? explain any one solution in detail (9)

OR

- Q3. Compare various encoding techniques. which is most suitable foe FPGA? why?(9)
- Q4. Differentiate synchronous asynchronous machine.(6)

## UNIT TEST-I (2009-10)

CLASS:- BE(E & TC) SUB:- VLSI DESIGN MARKS:-30

Q1] Explain VLSI design flow in detail with respect to EDA tool.(9)

Q2] Write VHDL code for 4 bit shift register for SISO operation.(9)

OR

Q3] Draw the state diagrm and write VHDL code for traffic light controller(9)

Q3] Explain in brief: delta delay(4)

Q4] What is metastability?How to avoid it?(8)

OR

Q5] Differentiate between: (8)

a)Function and procedure

b)Signal and variable

# UNIT TEST-I (2011-12)

CLASS:- BE(E & TC) SUB:- VLSI DESIGN MARKS:-30

- Q.1) Explain design flow in detail.mention the tools used st each step.(5)
- Q.2) What are the different modeling styles of architecture.how to make a decision?(5)
- Q.3) What is metastability?(4)
- Q.4) Draw the FSM and write VHDL code for J-k flip flop.(6)
- Q.5) Write VHDL code for 8 bit shift register.(5)
- Q.6) Explain the basic architecture of CPLD?(5)

# BHARATI VIDYAPEETH'S COLLEGE OF ENGG. FOR WOMEN UNIT TEST-II (2009-10)

CLASS:- BE(E & TC) SUB:- VLSI DESIGN MARKS:-30

- Q1] Explain boundary scan in detail, what is BIST?(8)
- Q2] Explain JTAG. What are the various pins involved?(8)
- Q3] With suitable schematic explain stuck-at faults. What is meant by fault coverage?(9)
- Q4] Why is DFT needed and explain in brief with suitable example.(9)
- Q5] What is technology scaling? What are the effects of it?(8)
- Q6] Design 4:1 mux using transmission gates and compare schematic with conventional design?(8)

# BHARATI VIDYAPEETH'S COLLEGE OF ENGG. FOR WOMEN UNIT TEST-II (2011-12)

CLASS:- BE(E & TC) SUB:- VLSI DESIGN MARKS:-50

- Q1] a)Explain CMOS-OPAMP in detail,brief the concepts of ctive load,current mirror,constant current source,output stage etc.give supporting expressions.(10)
  - b)What are the technologies to improve Rout of current sink/source?Explain cascade current source in detail(8)
- Q2] a)What I sthe need of transmission gate .Explain TG in detail.Design a circuit 4:1 mux using TG.(8)
  - b)derive the expression for static an ddynamic powerdissipation ,compare them.(6)
  - c)Why is device sizising so important? Prove p=2.5Wr.(6)
- Q3] a) Write short note on (8)
  - i)Threshold voltage
  - ii)Hot electron effect
  - iii)Channel length modulation
  - iv)Noise margin
- b)Explore stuck at open and stuck at short in detail.(4)

### **UNIT TEST-II (2010-11)**

## CLASS:- BE(E & TC) SUB:- VLSI DESIGN MARKS:-30

Q1. With suitable schematic explain Anti-fuse, Sram, And Flash Technologies for PLD (9)

### OR

Q1. Differentiate CPLD, FPGA, ASIC (9)

Q2.What is selection criteria of CPLD/FPGA in the system (6)

Q3. What do you understand by global clock, system clock and local clock/ what is significance of

each(9)

### OR

Q3.Explain the architecture of DRAM cell (9).

Q4. Explain DRC And SRC (6)